



Time Resolved Photo-luminescent Decay Measurements of Infrared Materials

SAND2014-16680PE

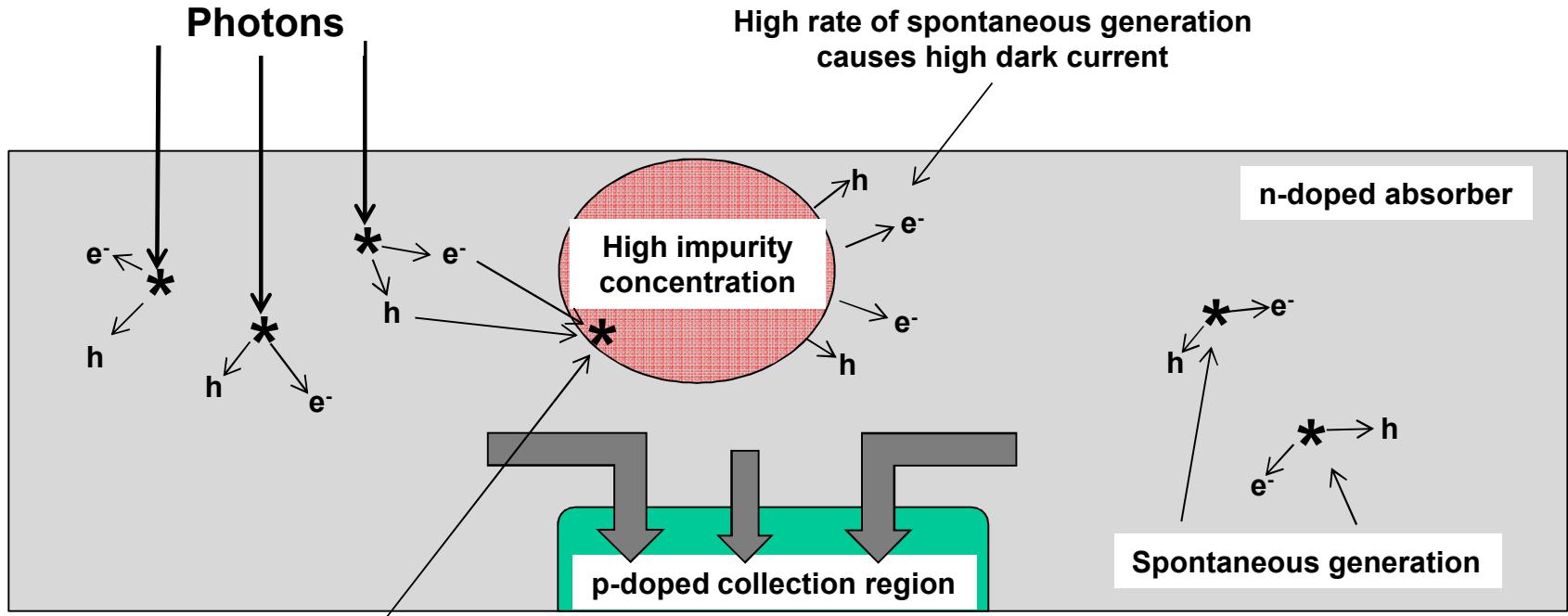
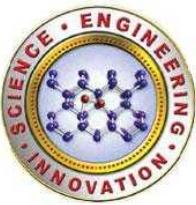


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Sandia National Laboratories
Laboratory Directed Research and Development (LDRD)
September 9th, 2014

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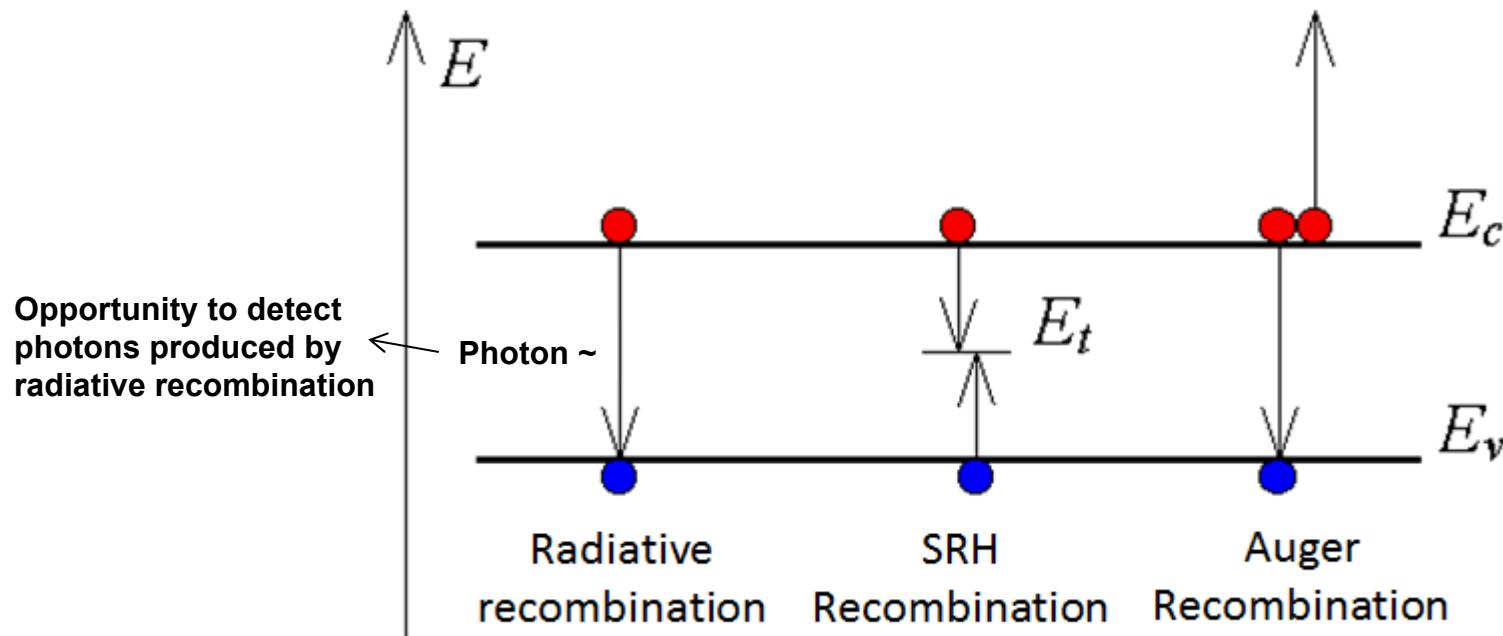
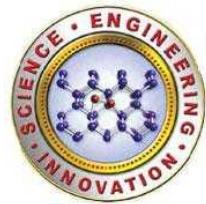
Carrier generation/recombination in a photo-sensitive device



High rate of recombination causes photo-generated carriers to be lost

- Carriers generated from photons that are collected are the signal we want
- Carriers spontaneously generated that are collected are dark current
- Carriers generated from photons that recombine contribute to reduced sensitivity

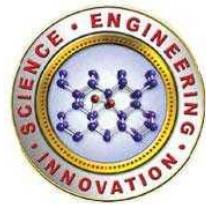
Semiconductor carrier recombination mechanisms



- Radiative and auger recombination rates are fixed for a given material composition
- SRH recombination occurs because impurities introduce energy states within the band gap that provide a path for carriers to recombine.
 - The rate varies depending on the impurity concentration(s)



Carrier recombination equations



Recombination Rates

$$U_{rad} = B(np - n_i^2)$$

Rates all dependent on a power of this term indicating the deflection of the system from equilibrium

$$U_{aug} = C_n(n^2p - n_0^2p_0) + C_p(np^2 - n_0p_0^2)$$

$$U_{SRH} = \frac{(np - n_i^2)}{\tau_{SRH-n}(p + p_1) + \tau_{SRH-p}(n + n_1)}$$

↑ SRH time constants ↑ SRH densities

$$\frac{\partial n}{\partial t} = \frac{\partial p}{\partial t} = G_{optical} - (U_{aug} + U_{rad} + U_{SRH})$$

Generation rate from photon absorption

↑ Net recombination rates (includes spontaneous generation rates)

Undoped

$$n_0 = p_0 = n_i$$

Intrinsic Concentration – material property

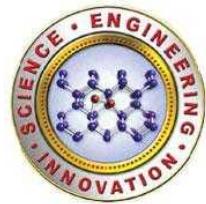
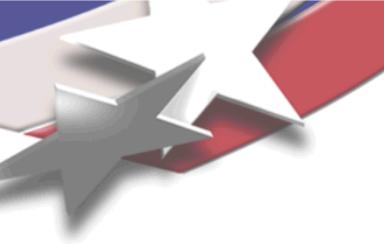
Doped

$$n_0 = \frac{N_D - N_A}{2} + \sqrt{\left(\frac{N_D - N_A}{2}\right)^2 + n_i^2}$$

$$p_0 = \frac{N_A - N_D}{2} + \sqrt{\left(\frac{N_A - N_D}{2}\right)^2 + n_i^2}$$

$$n_0 p_0 = n_i^2$$

↑ $n_0 \neq p_0$ for doped materials, but this equation always holds true

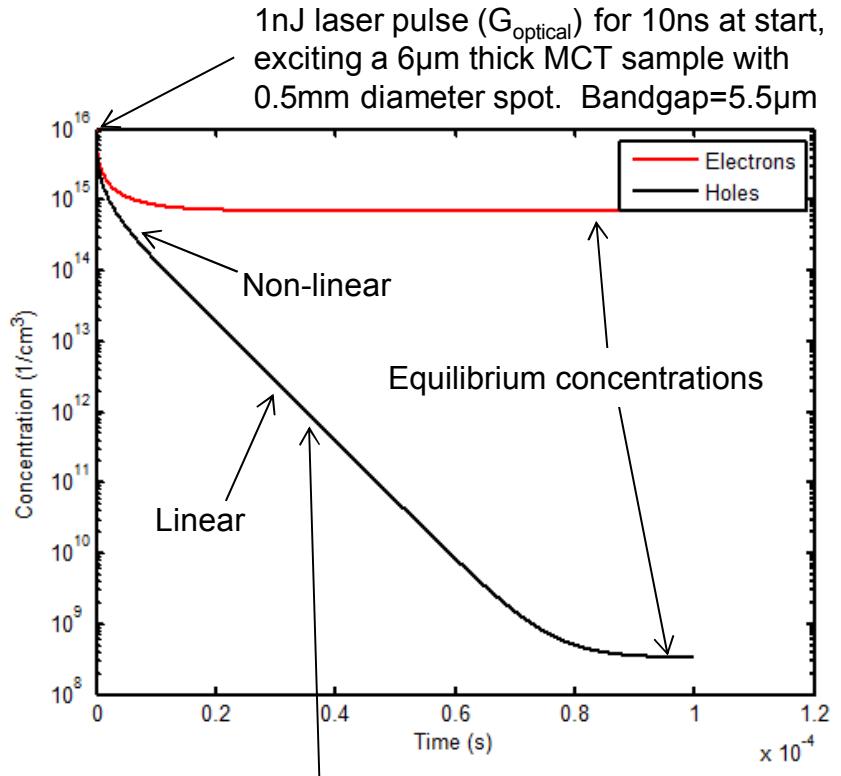


Carrier recombination numerical simulation

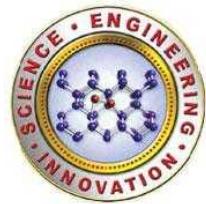
Inputs: starting concentrations $n(t_0)$ and $p(t_0)$ and laser pulse in time $G_{optical}(t)$

$$n(t + \Delta t) = n(t) + \Delta t \cdot G_{optical}(t) - \Delta t \cdot (U_{aug} + U_{rad} + U_{SRH})$$
$$p(t + \Delta t) = p(t) + \Delta t \cdot G_{optical}(t) - \Delta t \cdot (U_{aug} + U_{rad} + U_{SRH})$$

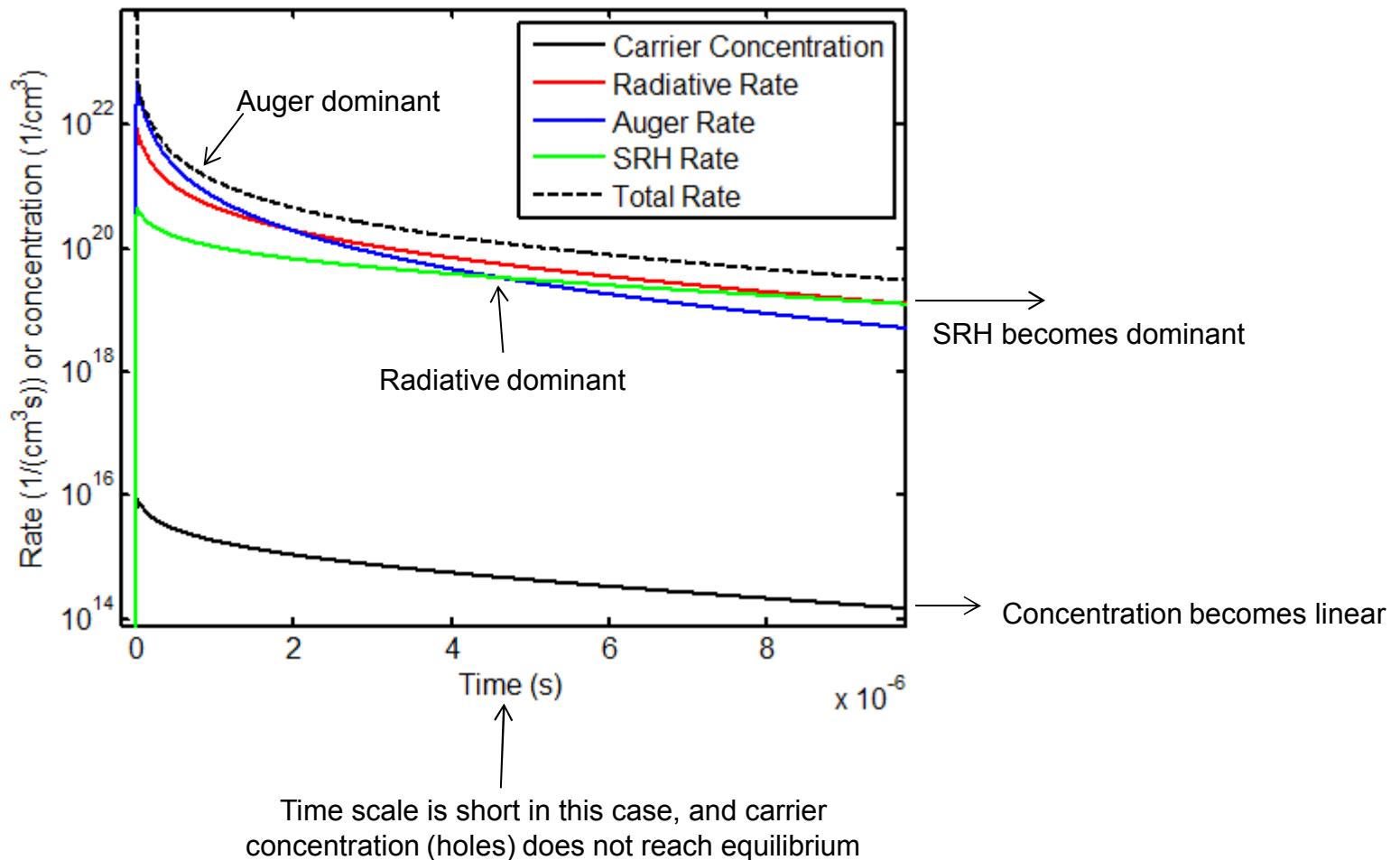
Δt is set at each iteration so the concentrations don't change by $>0.1\%$ for any given time step



Note: the deflection from equilibrium runs through ~ 6 orders of magnitude, cannot measure this much with an experiment

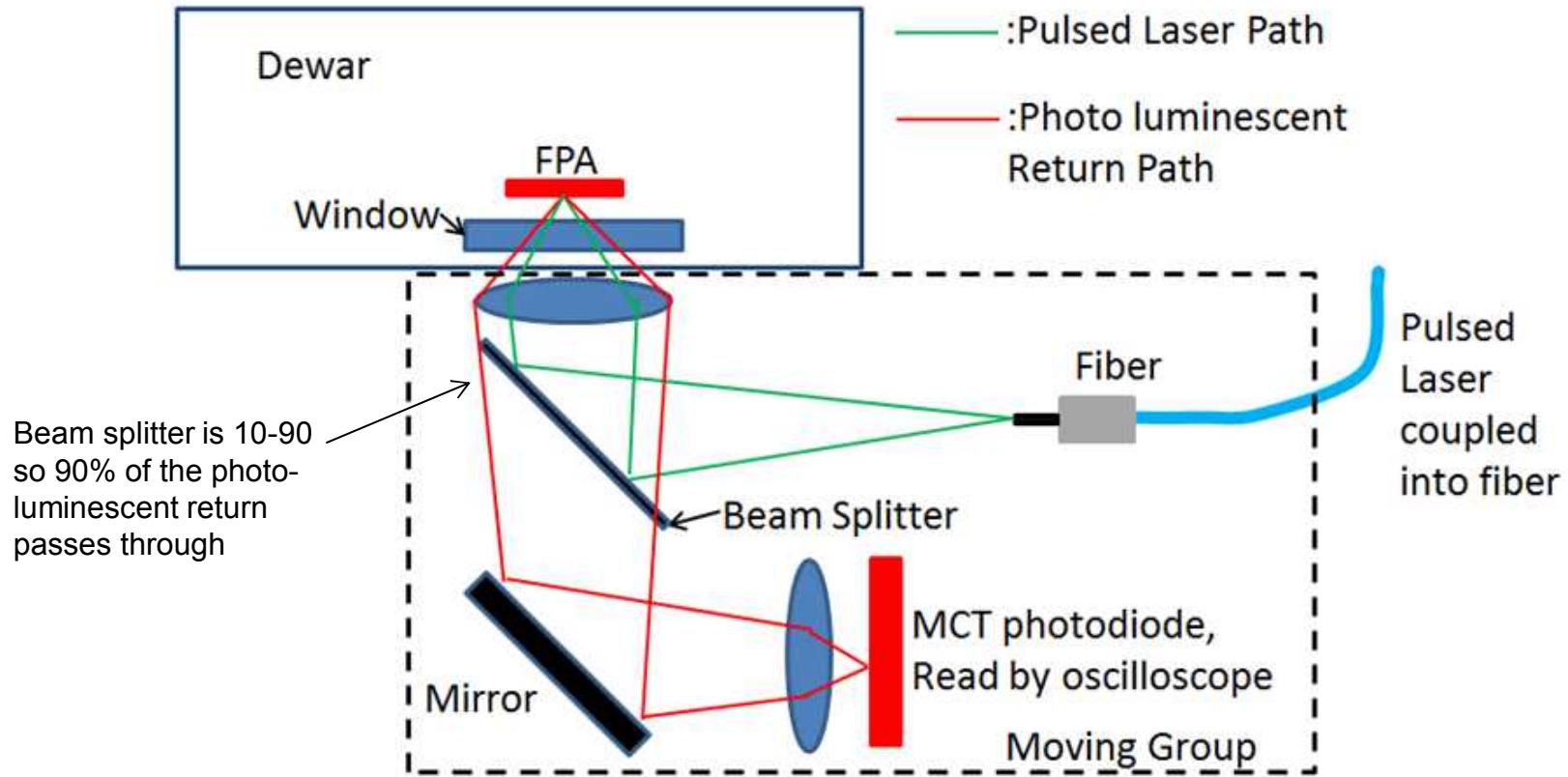
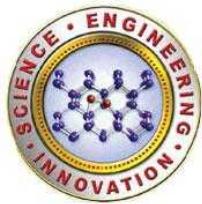


Recombination rates and carrier concentration



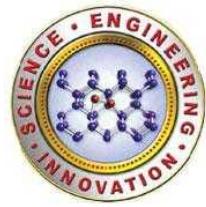


Time resolved photo-luminescent decay experiment diagram

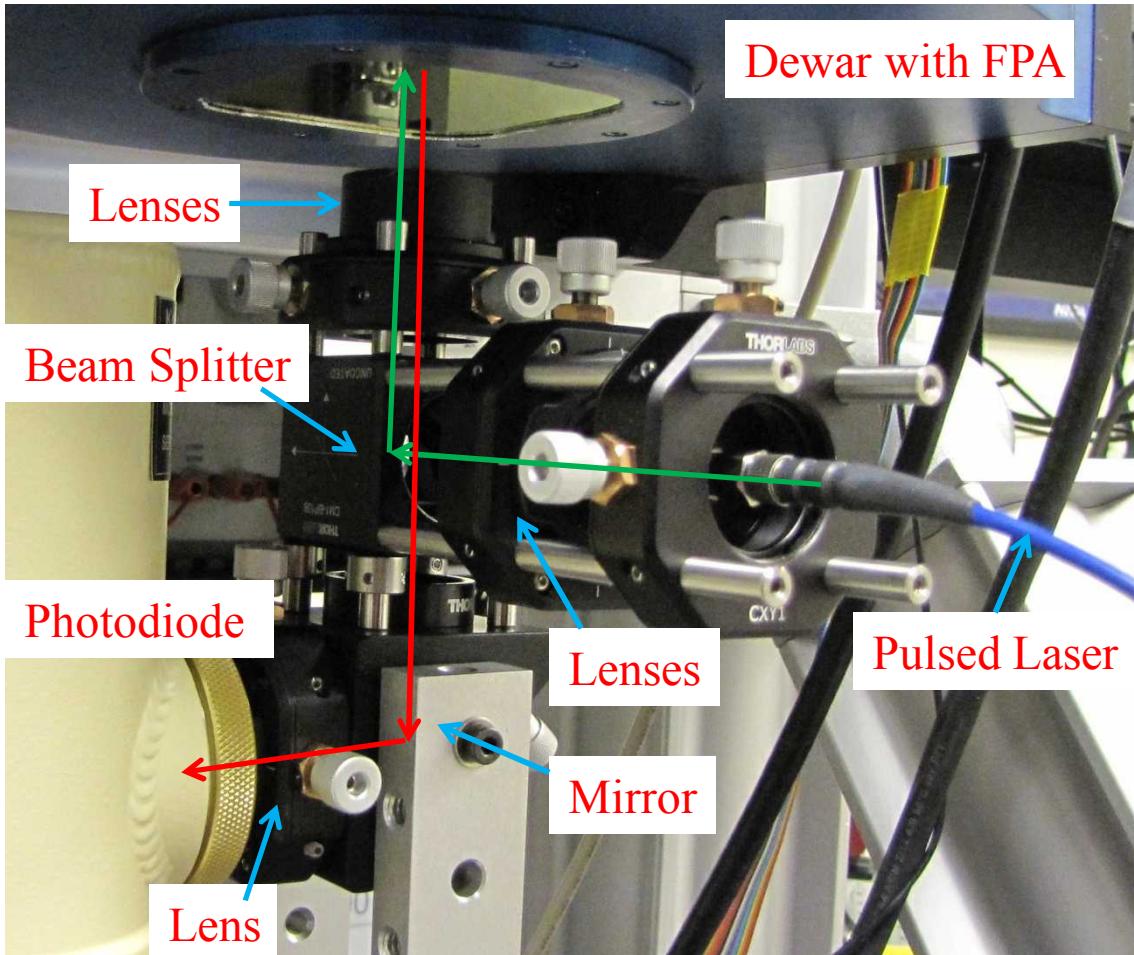




Picture of measurement station



8mm thick silicon window

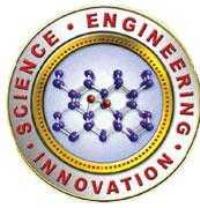
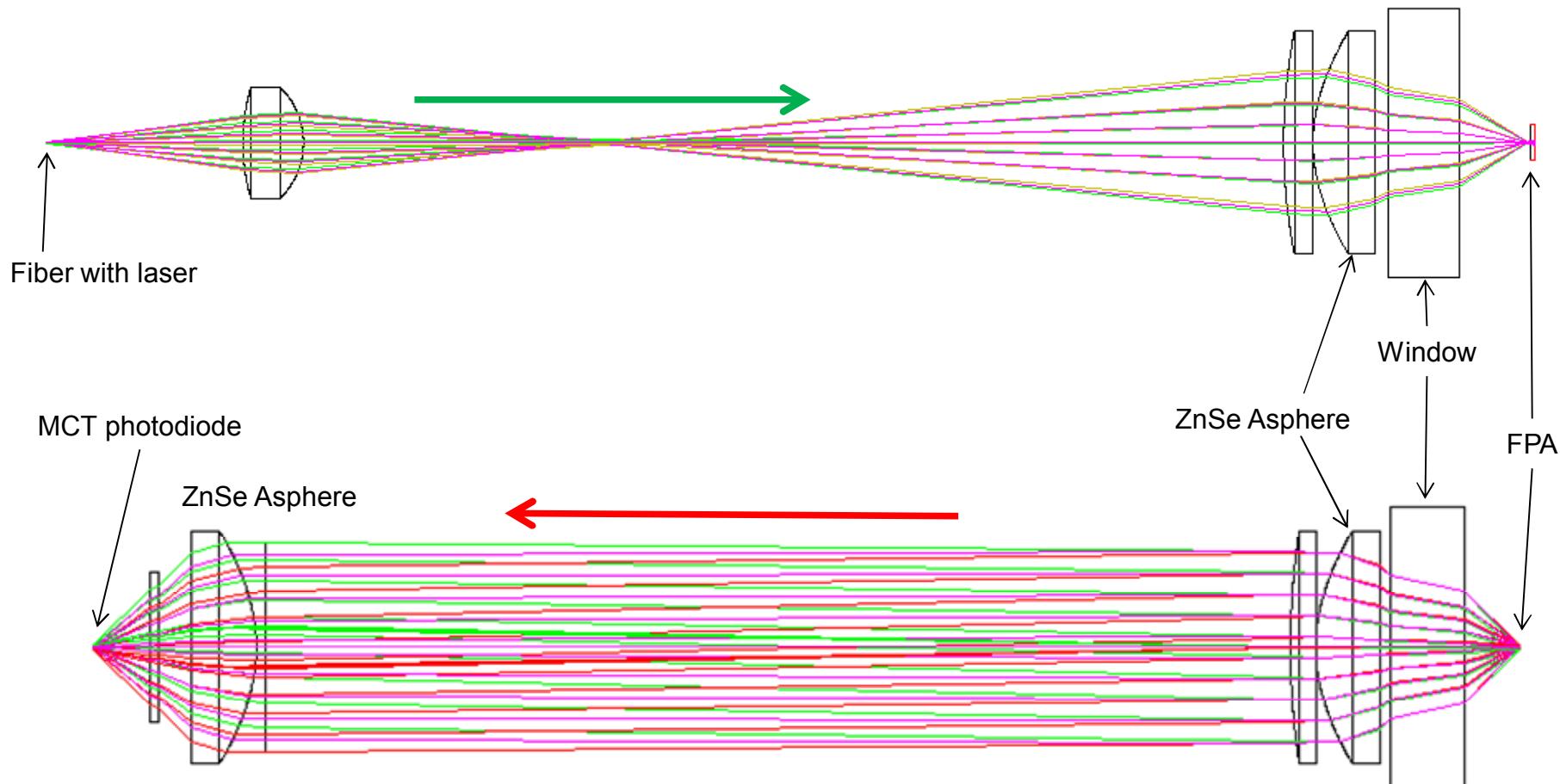


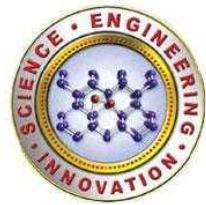
Kolmar 1mm
diameter MCT
photodiode

Ekspla OPO laser,
tunable from 2500-
4450nm

Newport XMS and GTS series stages

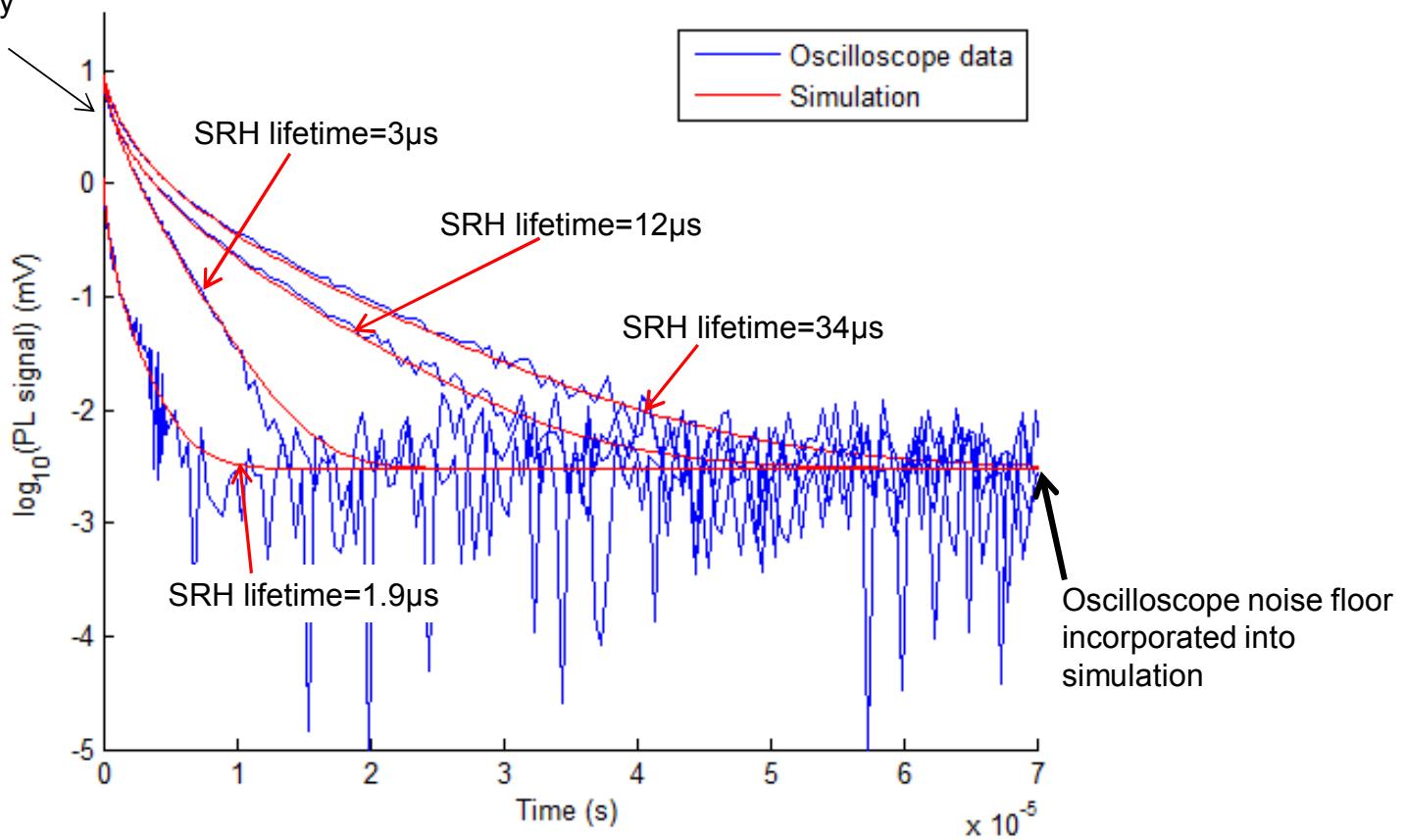
Optical design





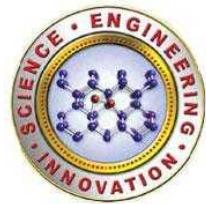
Comparison of data from different locations on an FPA

Time 0 for the simulation and optimization is actually set at 100-500ns after the laser pulse to avoid scattered laser light and detector rise/fall times affecting the signal

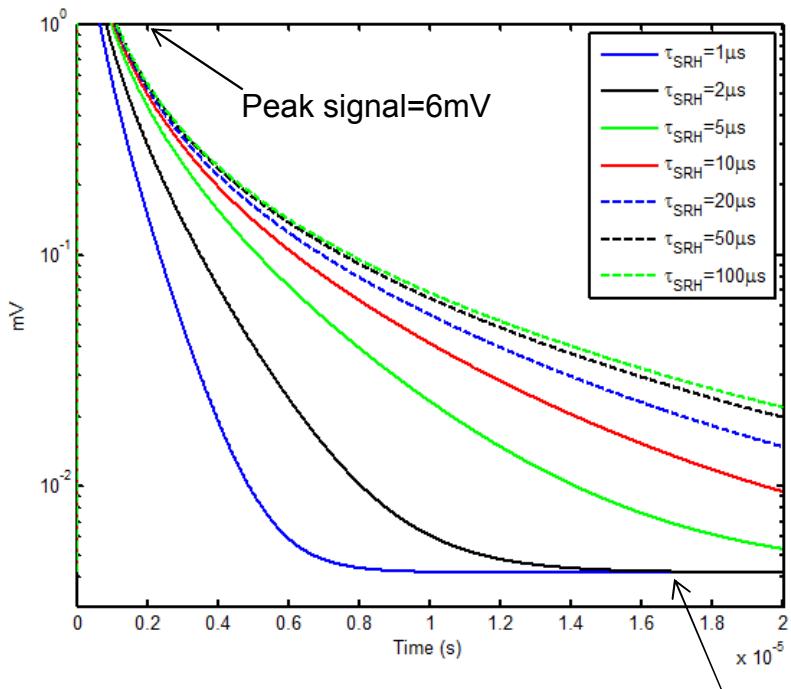


- The radiative recombination rate is proportional to the photon flux leaving the sample
- The simulation is used to scale the resulting radiative recombination rate to the oscilloscope trace
- The error between the simulation and data is optimized using Matlab fminsearch

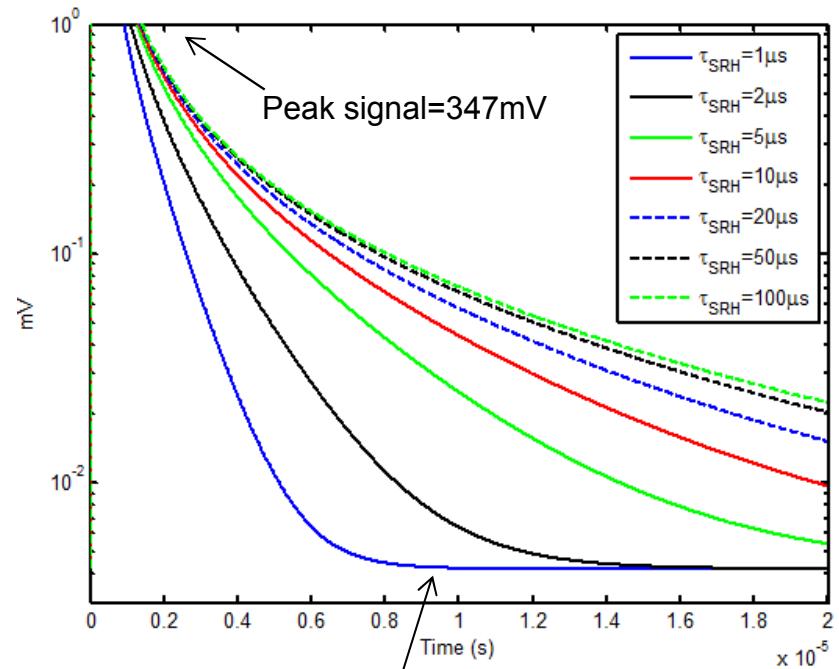
Simulation - effect of increasing excitation power



10ns, 0.5nJ pulse



10ns, 5nJ pulse

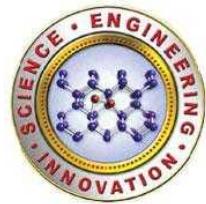


Typical noise floor was included in simulation

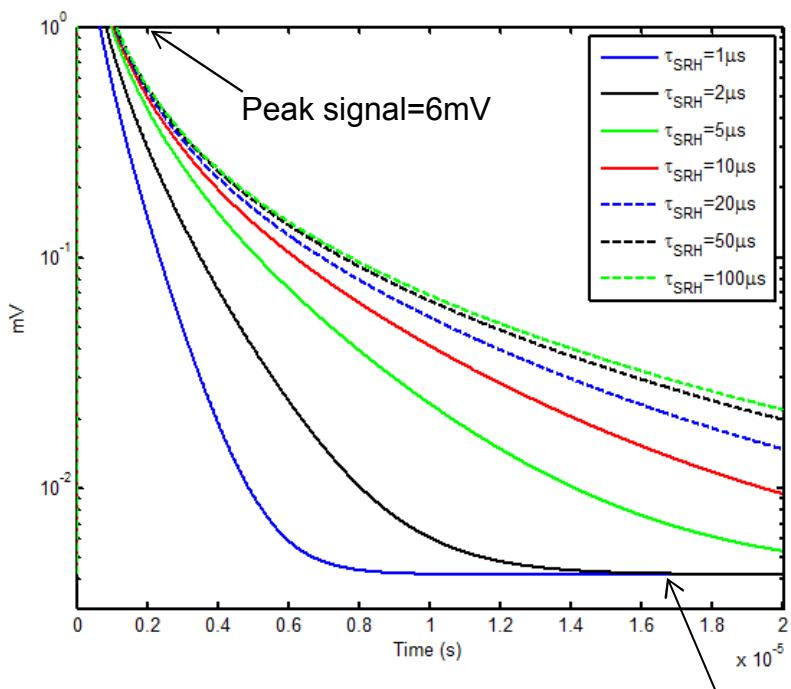
- Spot diameter is 0.5mm for all simulations
- Increasing the laser power only increases the magnitude of the short initial peak leaving the rest of the decay where the SRH lifetimes differentiate from each other nearly unchanged



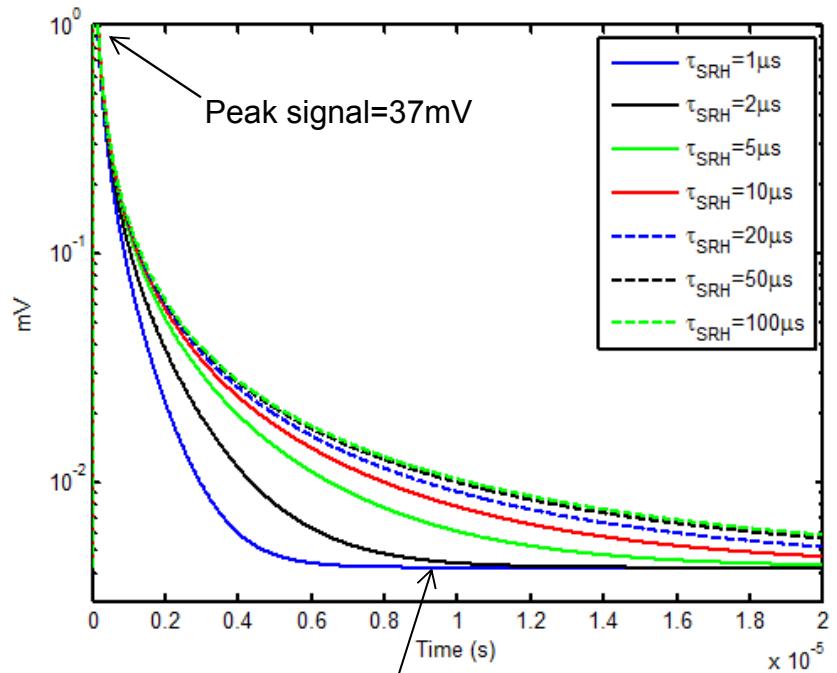
Simulation - effect of decreasing spot size



10ns, 0.5nJ pulse, 0.5mm spot diameter



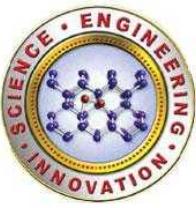
10ns, 0.5nJ pulse, 0.15mm spot diameter



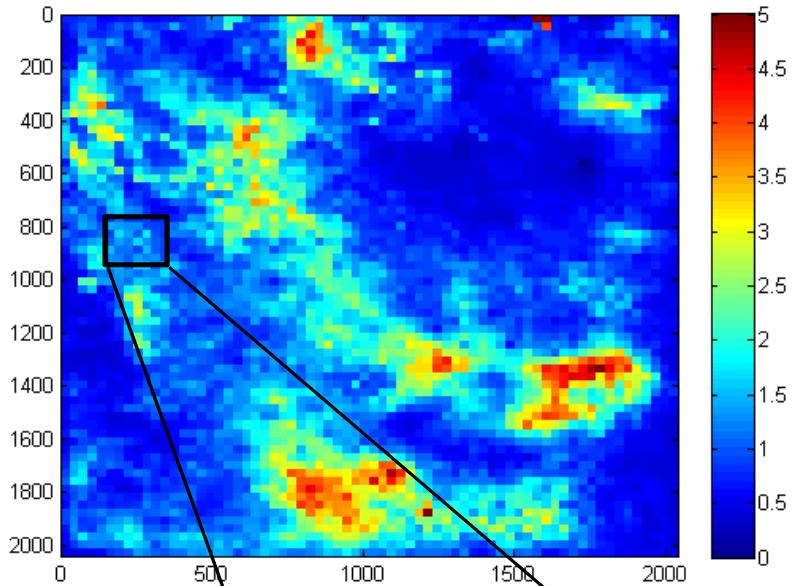
Typical noise floor was included in simulation

- The smaller spot diameter excites less volume, so less radiative photons are produced in the time range at which SRH lifetimes become distinguishable

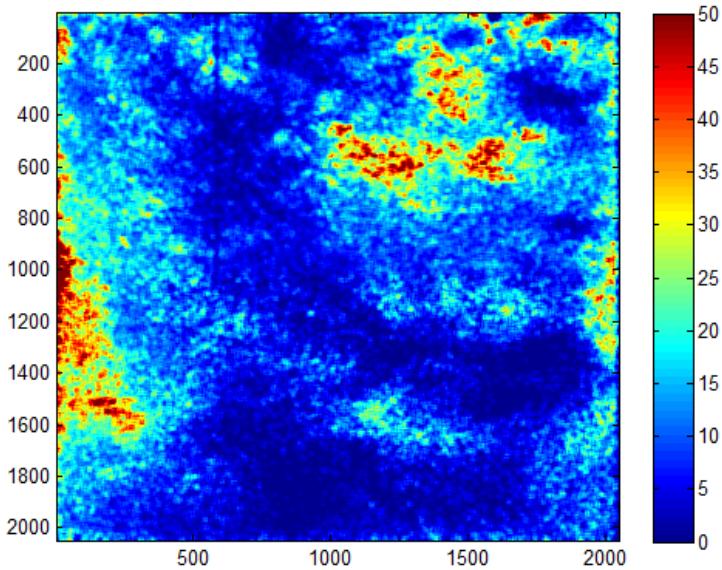
Lifetime maps for SWIR FPA #1



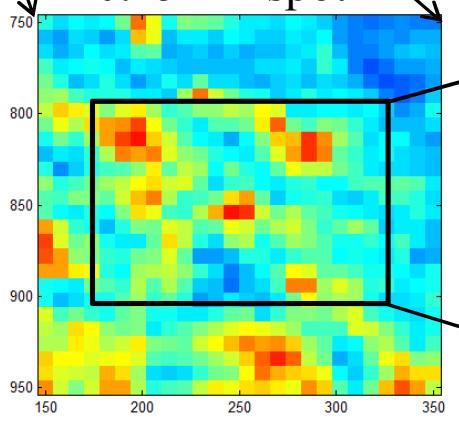
Lifetime (μ s), 0.5mm spot



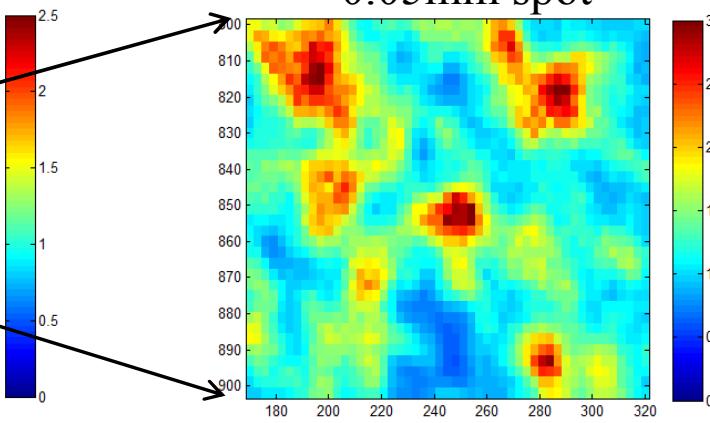
Dark Current (μ A/cm 2 @100K)



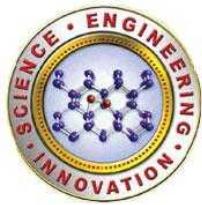
0.15mm spot



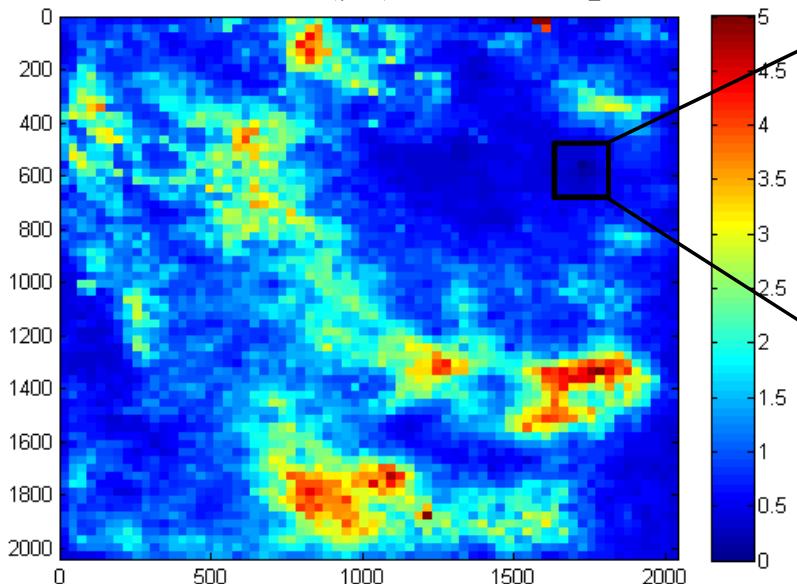
0.05mm spot



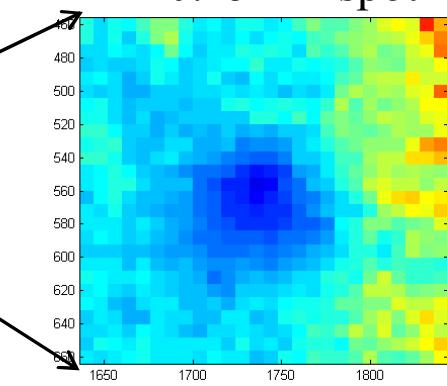
Lifetime and relative response for SWIR FPA #1



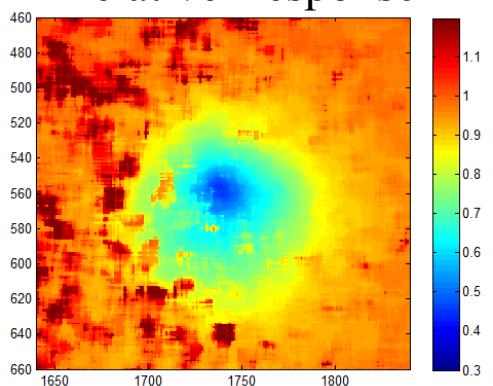
Lifetime (μ s), 0.5mm spot



0.15mm spot

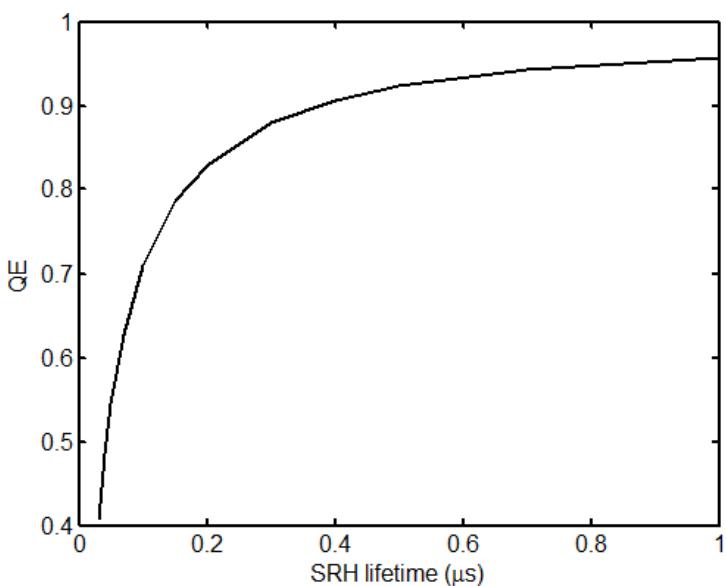


Relative Response



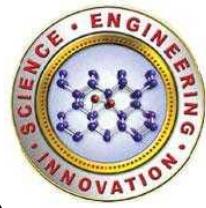
- Defect was found with ~ 100 ns lifetime, the lowest of any region in any of the 4 FPAs tested
- Charge diffusion model previously developed indicated that recombination before collection would reduce the QE at this short lifetime
- Relative response map confirms this

Charge diffusion model – QE vs. SRH lifetime

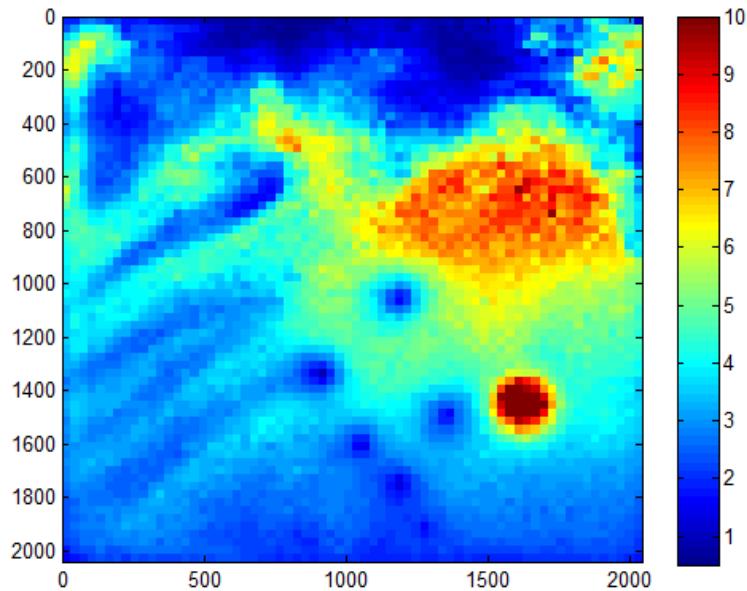




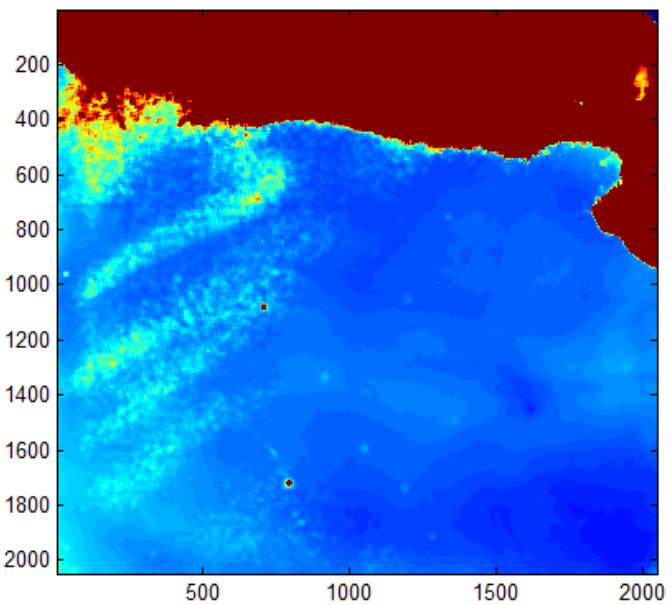
Lifetime map for SWIR FPA #2



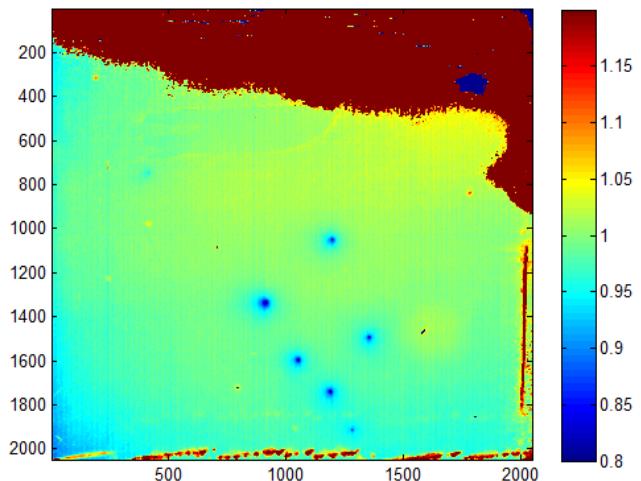
Lifetime (μ s), 0.5mm spot size



Dark Current (μ A/cm² @150K)

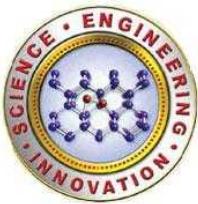


Relative response

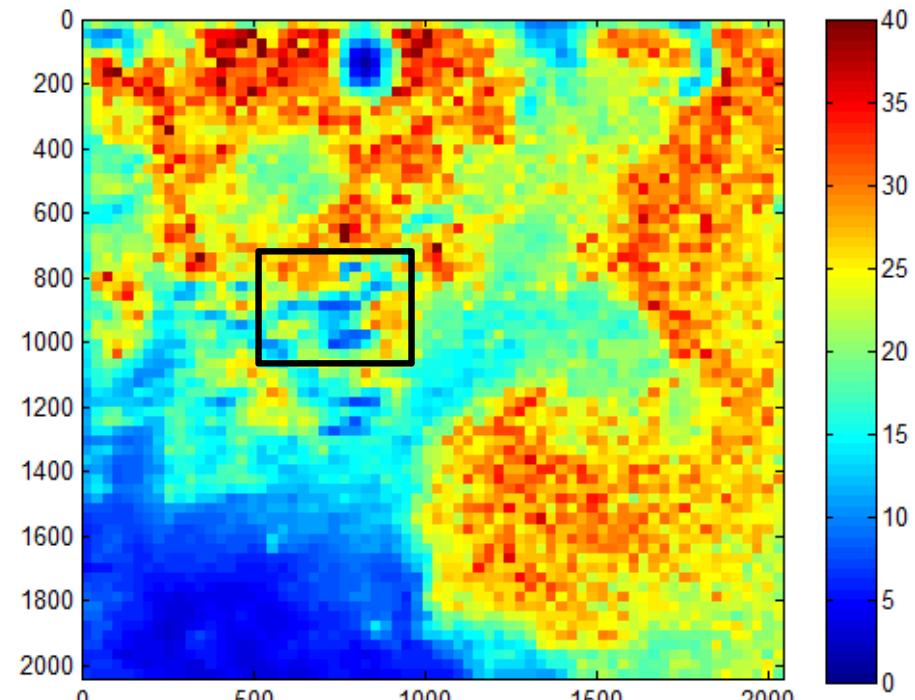




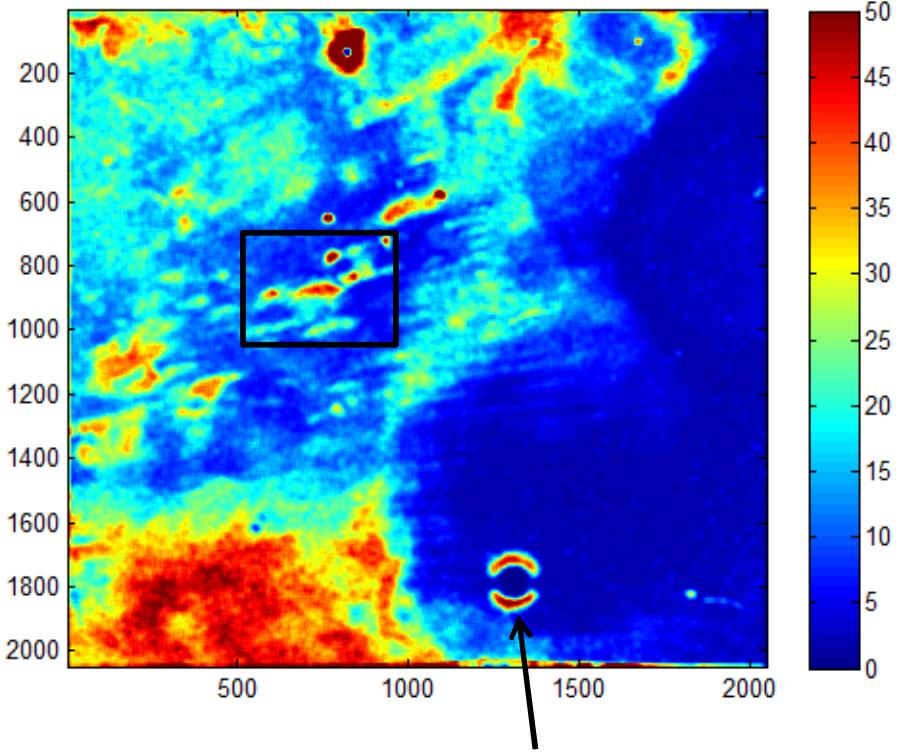
Lifetime map for MWIR FPA #1



Lifetime (μ s), 0.5mm spot size



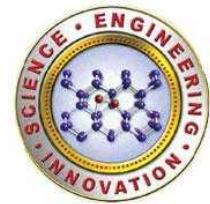
Dark Current (μ A/cm² @150K)



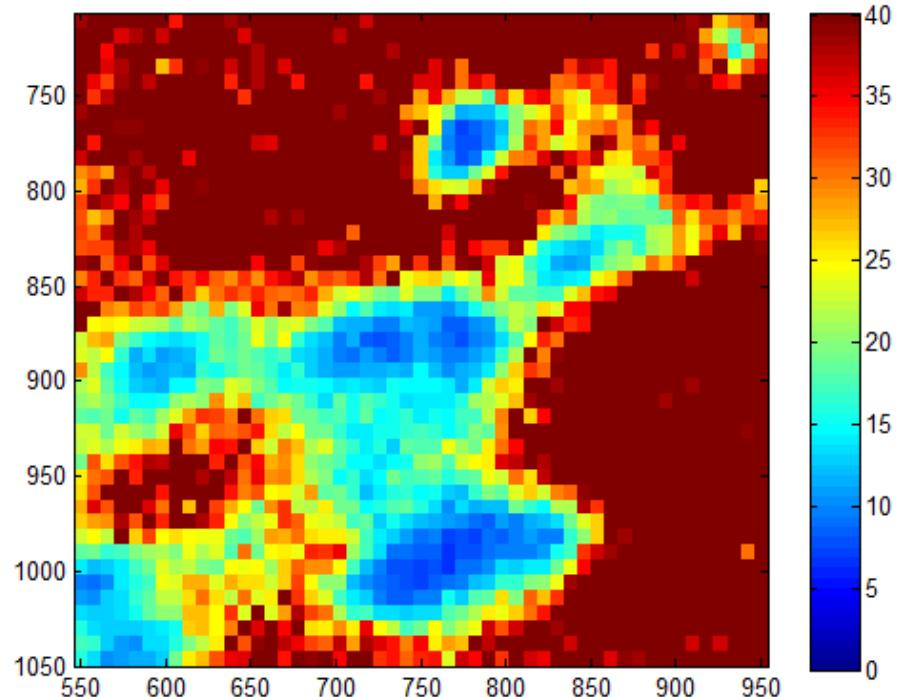
- Black boxes indicate the high resolution area of interest scan found on the following slide



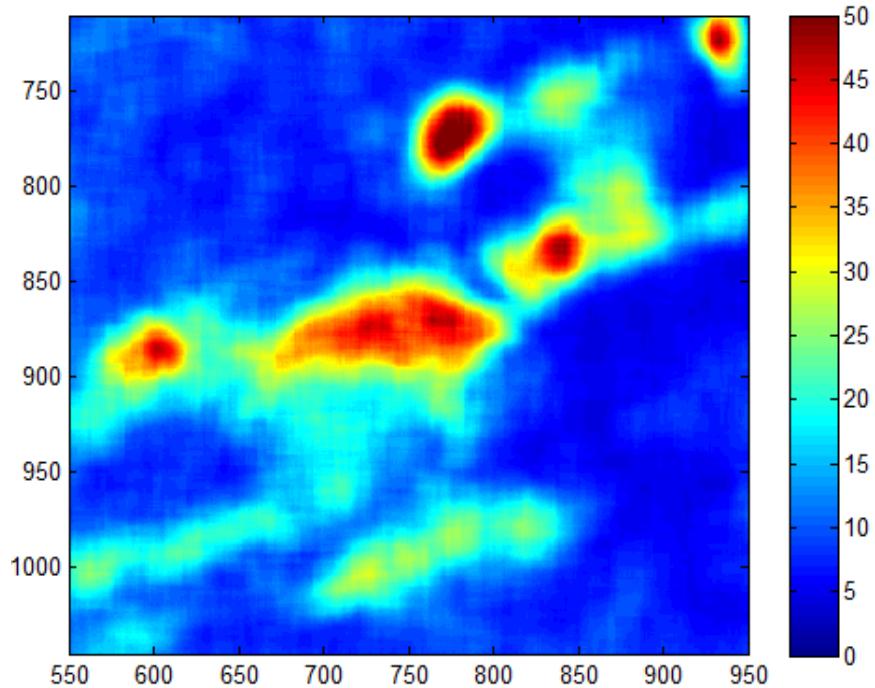
Lifetime map in area of interest, MWIR FPA #1



Lifetime (μ s), 0.15mm spot size

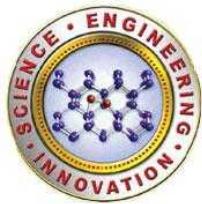


Dark Current (μ A/cm² @150K)

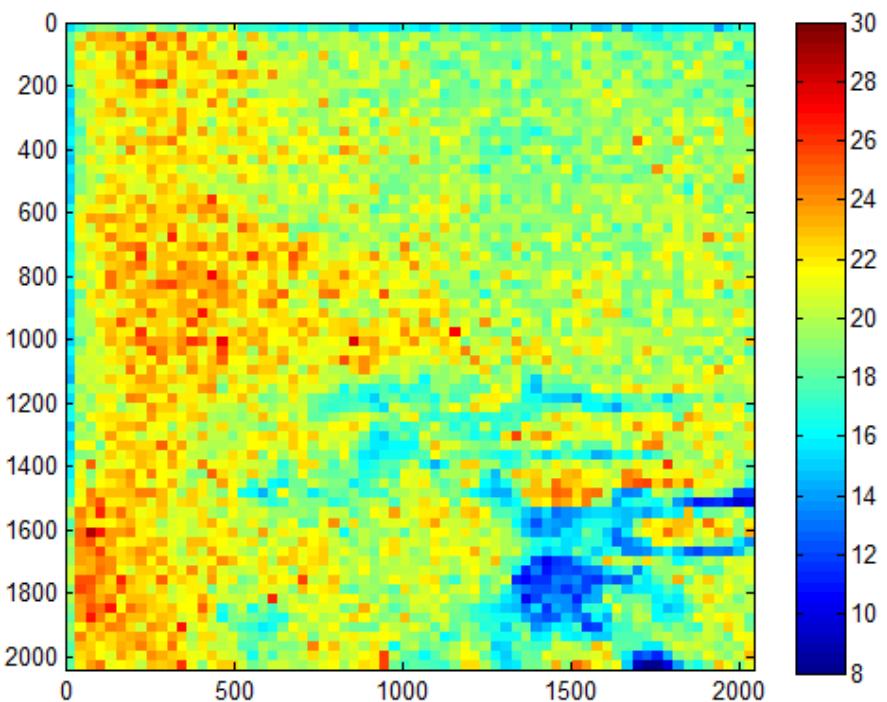




Lifetime map for MWIR FPA #2



Lifetime (μ s), 0.5mm spot size



Dark Current (μ A/cm 2 @150K)

